


<b>Search Notes</b>  	<b>Application/Control No.</b>  10521173	<b>Applicant(s)/Patent Under Reexamination</b>  OKUYAMA ET AL.
	<b>Examiner</b>  ANDREW P BAINBRIDGE	<b>Art Unit</b>  3754

SEARCHED			
Class	Subclass	Date	Examiner
222	192	3/31/08	APB
250	281-282,286-288,423f,423p,423r,424,435	10/20/2008	APB
378	66,119,210	10/20/2008	APB
361	225-228, 230-235	10/20/2008	APB

SEARCH NOTES		
Search Notes	Date	Examiner
Reviewed all IDS	3/31/08	APB
Angstrom and Nanometer	3/28/08	APB
Soft X Ray	3/28/08	APB
Backwards/ forward searched relevant references	10/20/2008	APB

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/A. P. B./ Examiner.Art Unit 3754	
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